Atomic Force Microscope

- First of it's kind high resolution microscope with **AFM, LSM** (Laser Scanning Microscopy), **WLI** (White Light Interferometry) and **FFOCT** (Full Field Optical Coherence Tomography) combined in one product !!

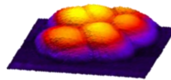
- Catering to the evolving requirements of applications in **Life Sciences**, **Materials** & **Micro-manufacturing**.

Features:

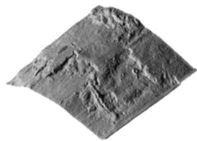
- The **AFM** - **WLI** - **LSM** - **FFOCT** combination generates complementary information.

- Enabling multiple analyses on single instrument covering **mm** to **nm** scale. Convenient switching between techniques without losing reference.

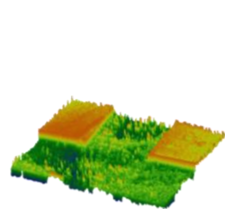
- **3D** imaging & analysis.



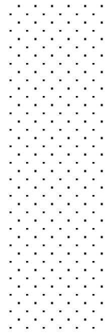
Bacteria cluster
ø 1 µm



Human hair
30 µm X 30 µm



µ-Fluidic
400 µm X 300 µm



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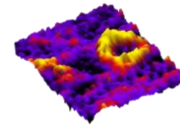
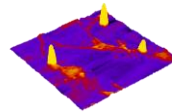
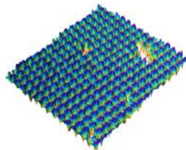


Plasmid
ht. 3nm, ø 500 nm



Exosomes
200 nm



Camera Sensor
90 µm X 80 µm

DSS IMAGETECH PVT. LTD.

A-5 Mohan Co-op. Indl. Estate,
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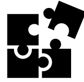
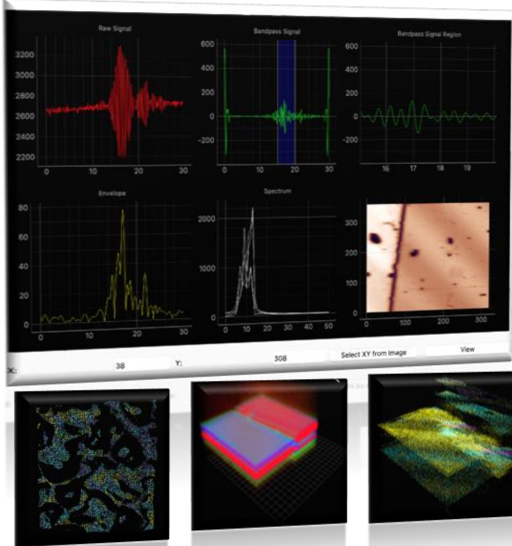
Software Features



Unleashing the Power of Lucent : Advanced Software for 3D Imaging and Analysis



Key features

- 3D visualization in volume mode, point clouds or as surfaces.
- Cross–sectional flyby mode, 3D measurements, spectral mapping
- HDF file format for large data handling
- GPU accelerated reconstruction & visualization
- Seamless compatibility with Gwyddion, the go-to software for SPM data analysis

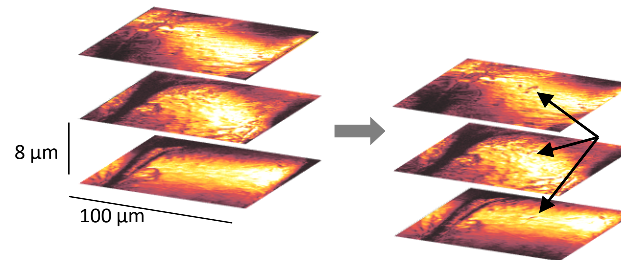
FFOCT - AFM

Revealing Hidden Dimensions: Structure, Depth, and Spectral Clues with FFOCT

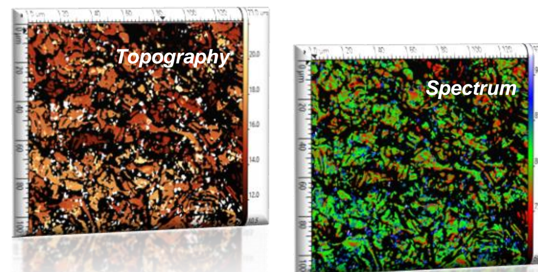
FFOCT enables 3D, subsurface & multilayer imaging with nanometer axial resolution. Integrated reflectance spectroscopy helps to characterize materials.

Application areas

- Biomedical Imaging
- Tissue & Organoids
- Archaeology & art conservation
- Semiconductor Metrology
- Coatings, Microfluidics, MEMS, Micro-optics
- Non Destructive Testing (NDT)

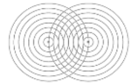


Subsurface plant cell membranes before & after AFM indentation



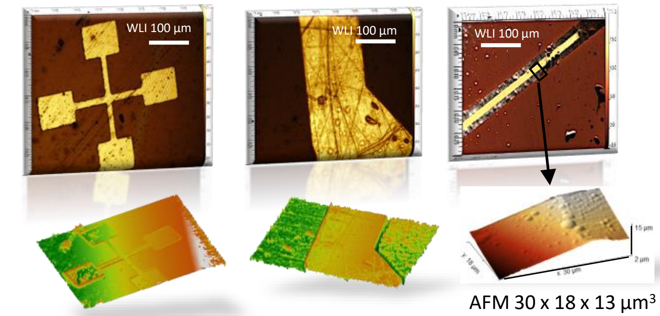
Biopsy histopathology sample 140 x 110 µm^2

WLI - AFM



Unlock the ultimate precision with the power of White Light Interferometry and AFM Fusion

The combination of WLI and AFM offers a powerful set of features for nanoscale characterizations.



AFM 30 x 18 x 13 µm^3

Wide range of material classes : Silicon chips, MEMS, Micro fluidics, Machining, electronic packaging, coatings & more.

- WLI provides long range profiling, feature search, defect analysis.
- AFM provides high resolution measurements, orthogonal characterization, surface roughness, nano-indentation.

Plant tissue pre & post AFM indent. WLI mode 120 x 110 µm^2